

PCN Number:	20190329002.1	PCN Date:	April 2, 2019
Title:	Qualification of AIZU as an additional Fab Site option for select CMOS9T devices and Datasheet update		

Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	July 2, 2019	Estimated Sample Availability:	Date provided at sample request.

Change Type:			
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process
<input type="checkbox"/>	Design	<input checked="" type="checkbox"/>	Electrical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>	Part number change

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its AIZU fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.

Current Sites			Additional Sites		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
MAINEFAB	CMOS9T	200mm	AIZU	CMOS9T	200mm

In addition, the datasheet number will be changing.

Device Family	Change From:	Change To:
LP8556	SNVS871J	SNVS871K

The LP8556 product datasheet is updated as seen in the change revision history below:



LP8556

SNVS871K – JULY 2012 – REVISED MARCH 2019

LP8556 High-efficiency LED backlight driver for tablets

4 Revision History

Changes from Revision J (January 2018) to Revision K	Page
• Added separate ESD Rating for the WQFN package - changed from "±2000" to "±1000".....	6

These changes may be viewed at: <http://www.ti.com/lit/ds/symlink/lp8556.pdf>

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland

New Fab Site

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
AIZU	CU2	JPN	Aizuwakamatsu-shi

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS
 MADE IN: Malaysia
 2DC: 2Q:
 MSL 2 / 260C/1 YEAR SEAL DT
 MSL 1 / 235C/UNLIM 03/29/04
 OPT: 39
 ITEM:
LBL: 5A (L)T0:1750

(1P) SN74LS07NSR
 (Q) 2000 (D) 0336
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: (Y) 0033317
(20L) CS0: SHE (21L) CCO: USA
 (22L) AS0: MLA (23L) ACO: MYS

Product Affected Group:

LP8556SQ-E00/NOPB	LP8556SQE-E00/NOPB	LP8556SQE-E09/NOPB	LP8556SQX-E08/NOPB
LP8556SQ-E08/NOPB	LP8556SQE-E08/NOPB	LP8556SQX-E00/NOPB	LP8556SQX-E09/NOPB
LP8556SQ-E09/NOPB			

Qualification Report

Approve Date 1-Feb-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: LP8556SQE0WZ85	QBS Product Reference: LP8556SQE	QBS Product/Process Reference: LP8556TMX-E09/S1	QBS Package Reference: LMH6517SQE/NOPB	QBS Package Reference: DS25CP102Q SQ
AC	Autoclave	96 Hours	-	-	-	1/50/0	2/154/0
ED	Electrical Characterization	(Per Datasheet Parameters)	1/30/0	-	-	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	3/913/0	-	3/1599/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	2/154/0	-	-
HAST	Biased HAST, 110C/85%RH	264 Hours	-	-	1/77/0	-	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	1/77/0	-	1/77/0
HTOL	Life Test, 125C	1000 Hours	-	-	3/228/0	-	2/153/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	3/231/0	2/154/0
THBT	Temp Humidity 85C/85%Rh	1000 Hours	-	-	-	-	2/154/0
uHAST	unBiased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	-
HBM	ESD - HBM	1000 V	1/3/0	1/3/0	1/3/0	-	-
HBM	ESD - HBM	2500 V	-	-	1/3/0	-	1/3/0
CDM	ESD - CDM	1000 V	-	-	1/3/0	-	1/3/0
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	-	-	-
LU	Latch-up	(per JESD78)	1/12/0	1/12/0	3/36/0	-	1/6/0
MQ	Manufacturability (Assembly)	(Per Mfg. Site Specification)	1/Pass	-	-	-	-

- QBS: Qual By Similarity

- Qual Device LP8556SQE0WZ85/NOPB is qualified at LEVEL1-260C

- HBM Electrostatic Discharge Sensitivity in datasheet shall be changed to new measured values

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com